

# R&D autour d'un Si-W ECAL

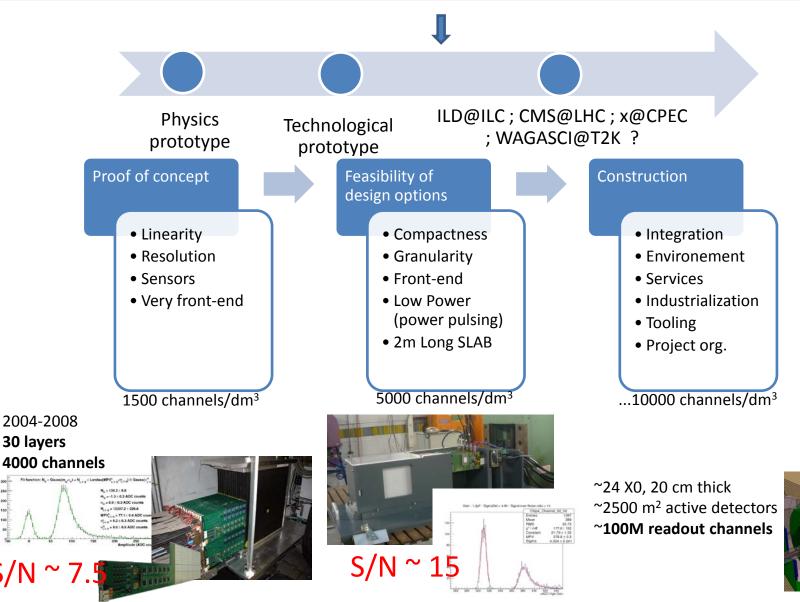
R. Cornat, LLR remi.cornat@in2p3.fr







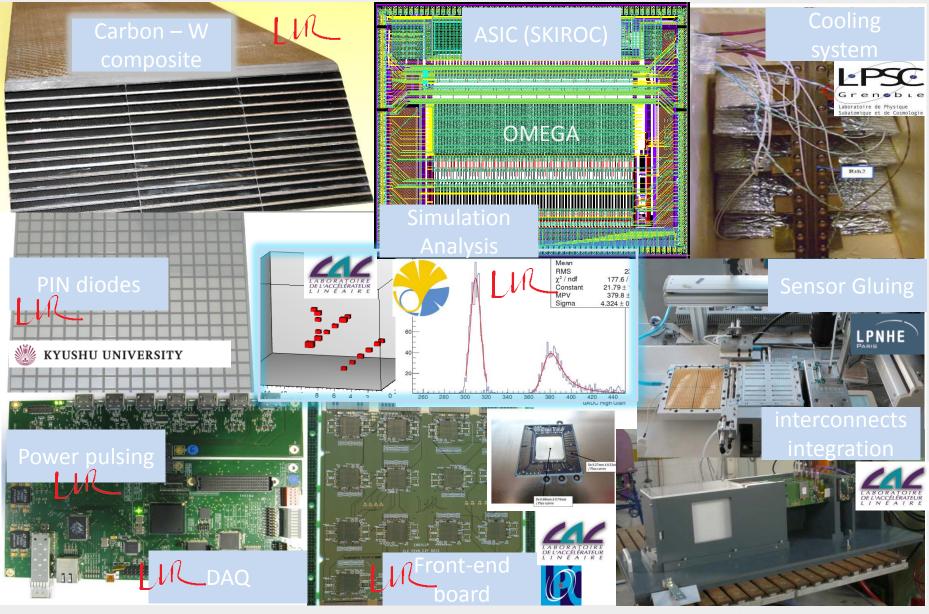
# Time line







#### Prototyping : who is doing what

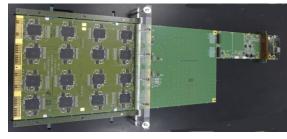




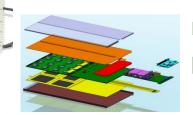
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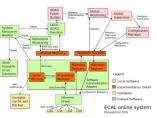
## Activities at LLR (CALICE)











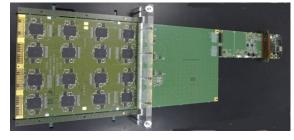
	Sensors	VFE & FE boards	DAQ	Integration & super-structure	SW ecosystem s for ECAL
<2015	· ·	-VFE : 256 chn, not opt -Universal Det. Interface -Test tools (w/o gluing)	-Universal DAQ for small throughput -Moderate power	Prototypes -Composite struct. -Single layer slab -Cooling, Gluing	<ul> <li>configuration &amp; raw data storage</li> <li>Det &amp; test bench</li> </ul>
2015	-Test tools -Larger size13cm -LFoundry -Small prod tests	-VFE : 1024 chn. -Long slab (4 boards) -Partial Opt. of PSRR & interchip couplings	-Partial inclusion of DIF functionalities: towards a local controller 100kchn	-Small prod of ASUs -Test with cosmics -Slim slab design	-Extended with data logger, pre-processing, run control
future	-Harvesting new manufacturers -Mass tests tools	-Longer slab (8 boards) -System redesign (PSRR) -Power distribution		-Design update -Long slab -Consolidated proto. -Tools -Beam tests	-Connexions to other sub-syst. -Event bulding



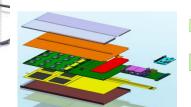
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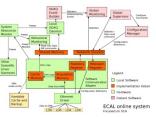
#### Project activities (mid term)











	Sensors	VFE & FE boards	DAQ	Integration & super-structure	SW ecosystem
outcome	-HPK w/o GR	-performance of single (few) channel(s) with power pulsing and SK2	-Modular system for Small setups	Prototypes -Composite struct. -Single layer slab -Gluing	-Modular SW -Diffusion among partners
ongoing	-Lowering dead area	-understand self couplings -Performance with beam -		-Semi-automated Integration bench	-Add function.
issue	Rad. Hard. New GR struct. (larger panel of manuf.)	-System redesign for SK2: PSRR, PP -New chip ? -Chip on board	-Higher level data Concentrator - Real low power -LV & HV distribution -DCS and system	-reproducibility -Full integration with cooling, top of module elec. & structure	-Double layer slab -Long slab -Consolidated proto. -Tools -Beam tests





5

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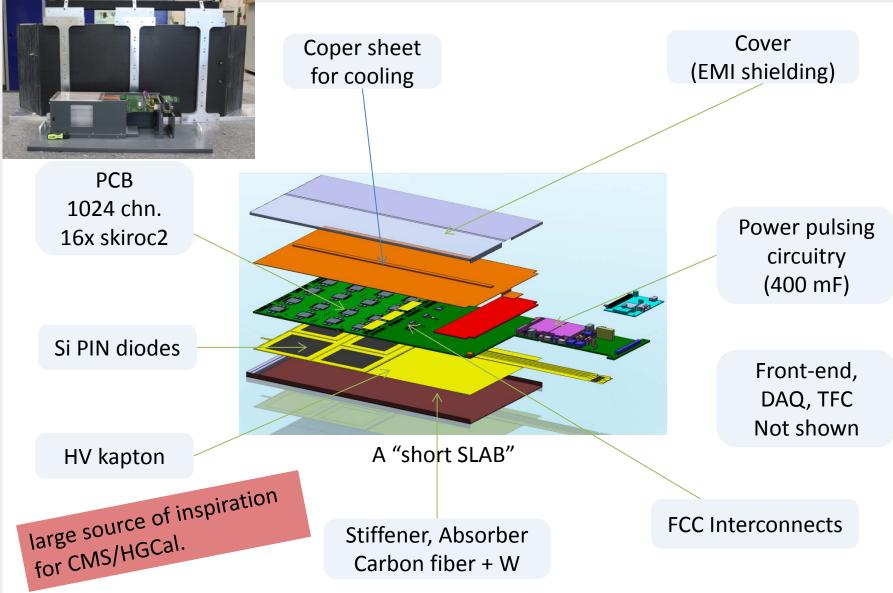
### Long term activities

- Scaling to an experiment depends...on the experiment (not the scope of current activities)
- But: on going R&D based on requirements for ILC (since 2006) for the demonstration of the concept
- Gain of credibility with a well integrated prototype (was EUDET prototype)
  - Needs funds and manpower (buy sensors, intrinsic cost of serious hardware, prototyping iterations, etc...)
  - Needs a definition of the project and its management
  - Many spin-off (LLR): CMS/HGCal, T2K, JUNO, CPEC, ILC...
  - Demonstration in the following:





### A detector module + composite structure

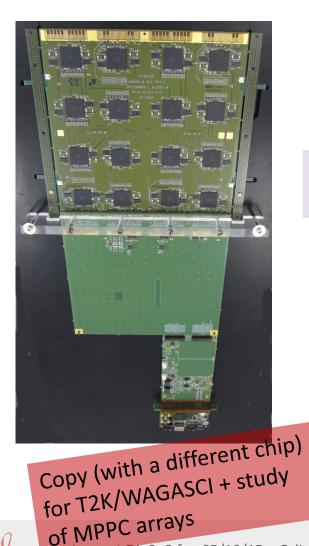






# Next version(s) of VFE board

18 x 18 cm<sup>2</sup> front-end board includes 1024 channels (16 chips), almost perfect flatness required for gluing the sensors : 1.6mm symmetrical stacking



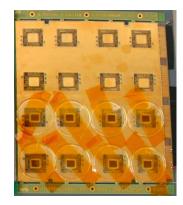
LFBGA packaged chips and Panasonic Sp-CAP CX series ⇒ 1.1mm thick components envelop



With packaged chips version the overall module thickness would be 5.5 mm (+absorber) : >4600 ch/dm<sup>3</sup>

Naked die version would provide optimal module thickness (<4mm in total, >6000 chn/dm<sup>3</sup>)

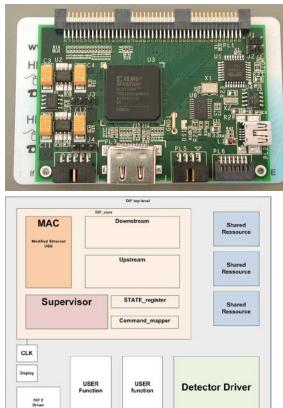
Electrical tests are ok but flatness is incompatible with sensor gluing.





### DAQ

#### DIF







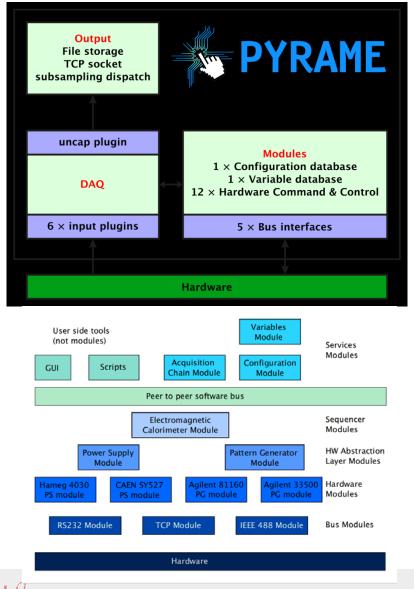
Baseline for T2K/WAGASCI + JUNO/Trigger-DAQ Read out of SKIROC2, SPIROC2, MAROC3, EASIROC...





9

#### SW http://llr.in2p3.fr/sites/pyrame/



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Prototyping framework for online systems. Heavily modular for control-command or data acquisition.

Flexible and providing lots of options, allowing the system to evolve as fast as the testbench.

Baseline for T2K/WAGASCI Used on P2IO/captinnov platfom

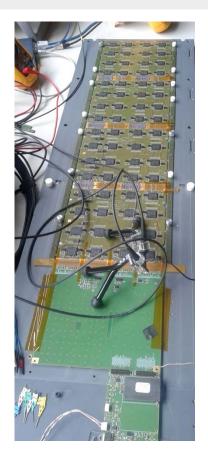
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Used on CILEX/Galop
Used on CTA/NectarCam test
benches
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Proposed to CMS/HGCal and JUNO (small setup DAQ)

Used on many LLR testbenches And at LAL & Japan for ECAL test benches

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### Latest news @LLR

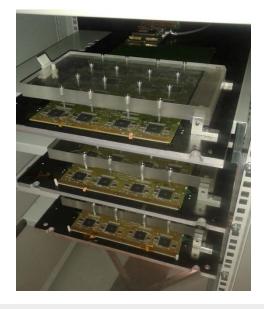


Long slab with 4096 channels : Configuration ✓ ok Read-out ✓ ok

Study of long transmission lines with high capacitive load : × on going Study of power distribution : × on going

Preparation of a test beam setup @CERN (Nov. 4-16 2015) : 3 planes ✓ok Slow control & Read-out ✓ ok

Study of long transmission lines with 4<sup>th</sup> plane : × on going Calibration : × on going





# Follow up of generic R&D 2016-17 @LLR

- Merging of DIF&(G)DCC : generic read-out HW , addressing issue of syncho, time stamping and time measurement.
- Designing long detector modules (CALICE as a study case)
   : R&D on transmission lines with high capacitive loads,
   power distribution (sim & proto), power pulsing
- Integrating the "EUDET" module : simulations of heat dissipation, miniaturized connections, stress tests of composite structures, slab design (CMS, ILC, CEPC)
- Toward the completeness of the online software : event building + integration with other frameworks (XDAQ, EUDAQ, etc...) and standards (OPCUA, IPBus,...)



# IT Manpower at LLR

Nom	Sujet	Generic (CALICE)	Specific
Michael Frotin	Intégration	10%	40% (CMS)
Marc Anduze	Structures	10%	25% (CMS)
Frédéric Magniette	Online SW	20%	80% (CMS)
Miguel Rubio-Roy	Online SW	20%	80% (LLR)
Jérome Nani	Instrumentation, DAQ	50%	50% (LLR)
Franck Gastaldi	DAQ	10%	90% (T2K, JUNO)
Rémi Cornat	Instrumentation, DAQ	40%	40% (JUNO, CTA)
		1.6 FTE	



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#### R Manpower at LLR

Nom		
Vladik Balagura		100%
Vincent Boudry		100%
Henri Videau		100%
Jean-Claude Brient		10%
Kostya Spack	PhD.	100%
Dan Yu	PhD.	100%
Trong Hieu -> Bo Li	PostDoc	100%
		3.1 + 3 FTE



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# 2015 Results

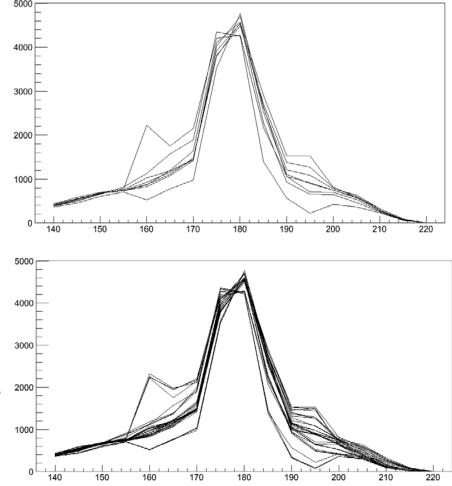




# I.2 Sensitivity to noise from other chips

Rough Scurves of a few selected reference channels on a reference chip

0, 8, 16 then 32 channels/chip are made noisy (trigger enabled + threshold set at 180 maximum toggling of internal triggers)



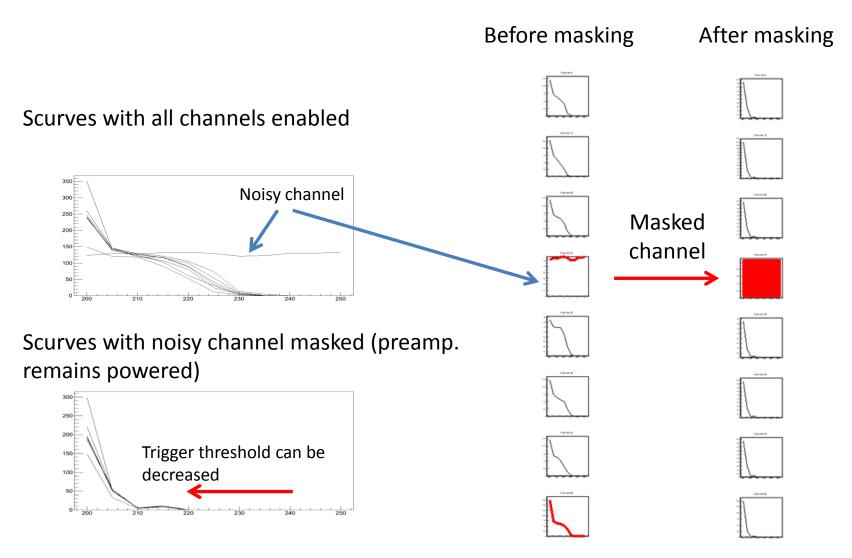
→ Reference Scurves remains the same whatever the number of noisy channels is

#### Courtesy of J. Nanni (LLR)





# I.3 Internal noise



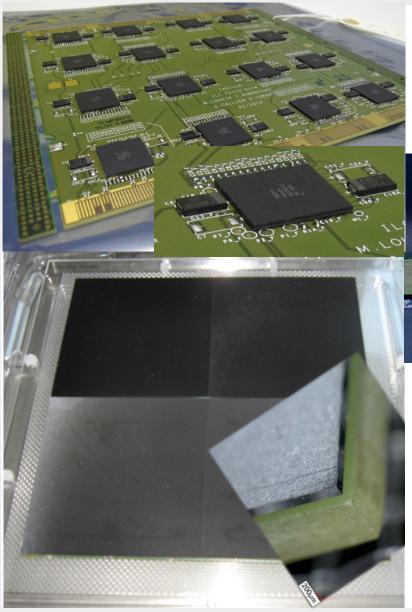
→ Digital noise due to generation of internal triggers



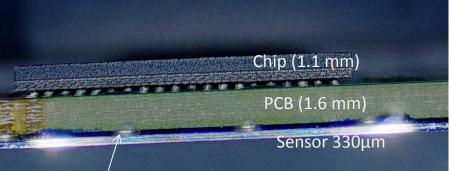
17

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### **Detector module assembly**



Robots for gluing sensors are developed (LPNHE) ⇒ First step towards industrialization



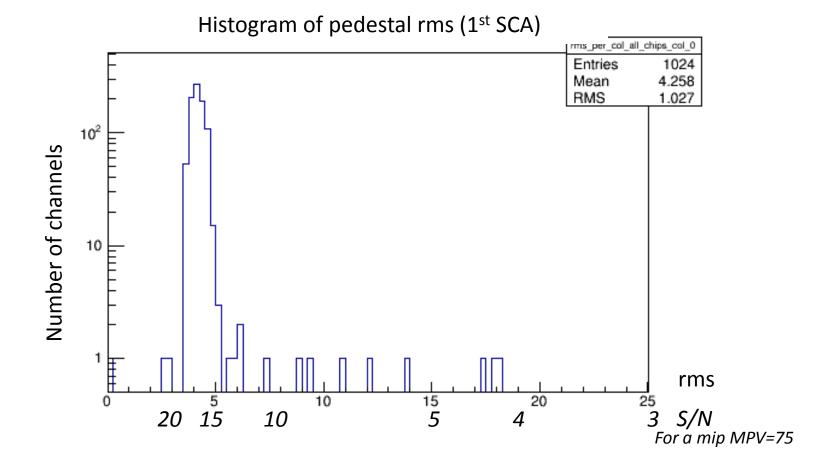
Conductive glue dots (200µm)

4 wafers 9cm x 9 cm wide can be glued with a 20  $\mu$ m precision and a reproducible process. Glue is dispensed then pressed in order to form 200  $\mu$ m thick dots



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## II.1 Pedestals with glued sensors



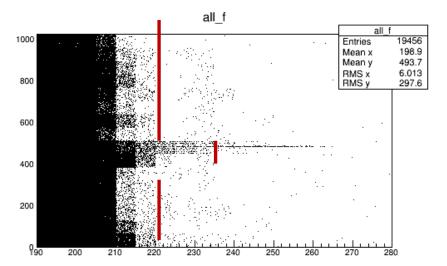
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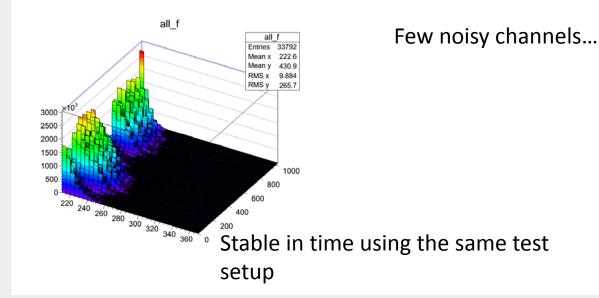
19

### II.2 Scurves

New cabling of the power supplies , isolated room

Uniform threshold arround 220-230 DACu possible



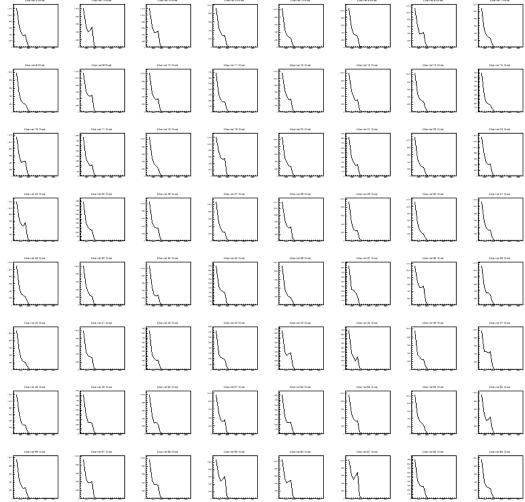




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#### II.2 Scurves

Probable effect of internal digital noise

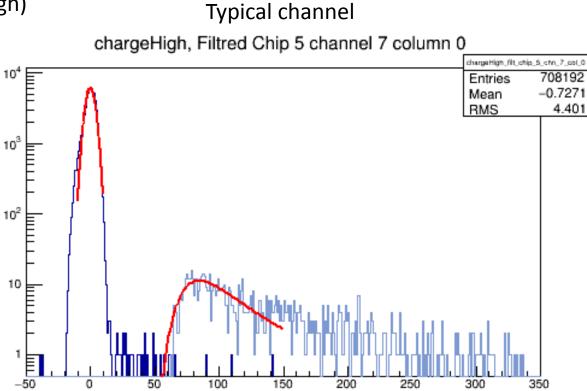




## II.3 Cosmics data taking

50 hours, Spill at 10 Hz, duty cycle 60% DIF in TestBeam mode

Gain: 1.2 pF (high)

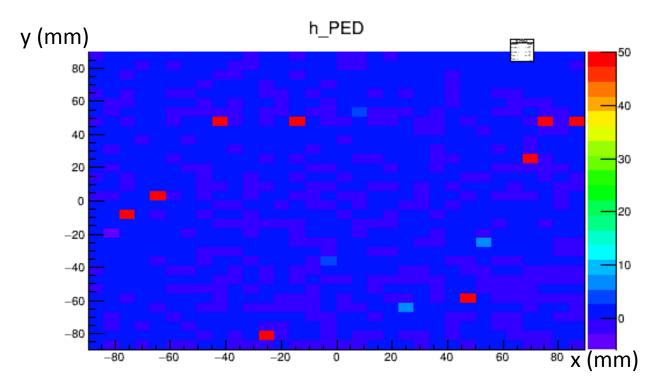




## II.3 Cosmics data taking

5 cosmics run taken, ~consitent

Pedestal uniformity after correction (= mean of gauss fit)



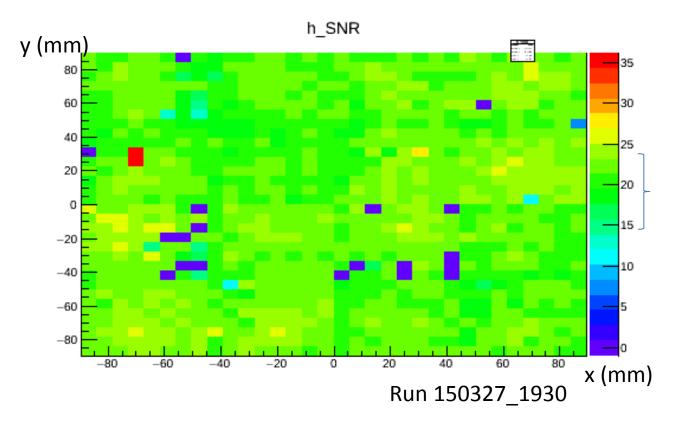
# II.3 Cosmics data taking : SNR

Some fit error + missing channels (to be verified)

Quality of fits not checked

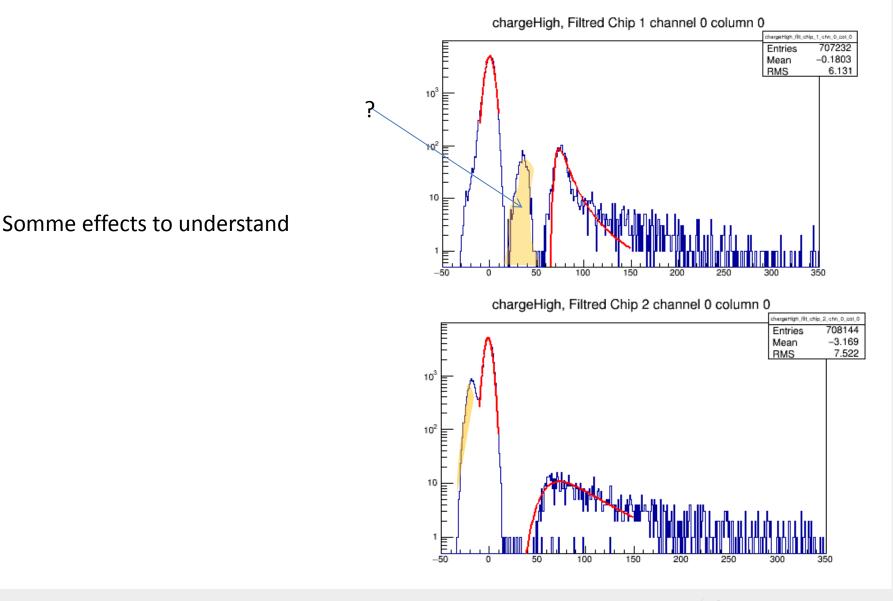
Part of landau can but cut (high threshold) : overestimation of MPV

... but preliminary results are encouraging!



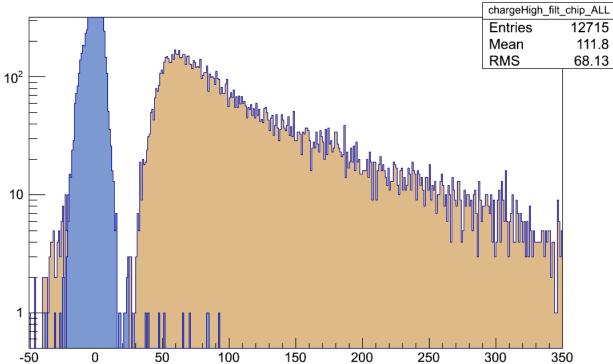


### II.3 Cosmics data taking



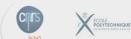


#### All channels of a chip merged together (raw data with no cut)



chargeHigh, Filtred ALL





# Toward a full length module

In principle, front-end boards will be chained forming up to 2m long detector SLAB, most of signals in bus

Issue 1 : clock distribution (5 & 50 MHz) Interconnects are not impedance controlled (FFC) One clock line may be loaded by 40 to 80 ASICS

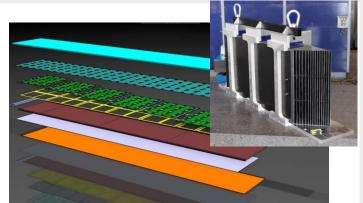
 ⇒ Use of MLVDS adapted with 100 Ω on both sides, 100 mVpp remaining signal at the end (6 Ohms loss/board, 20-40 pF/board, up to 10 boards)

⇒ Next version ASIC will have a PLL generating the highest frequency

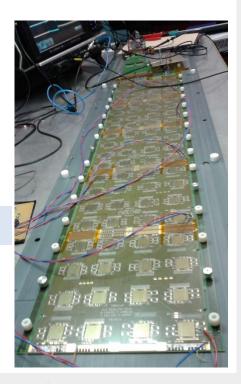
Issue 2 : Power distribution (12 A pulses) & blocking capacitors (tested with FET switches as loads)

 $\Rightarrow$  Current taken from a 800mF super cap (16m $\Omega$  ESR) + 2mF/board

Along 6 boards, static loss is 250 mV due to connectors (w/o chips).
May foresee to distribute power in a star topology.
4 boards SLAB being assembled at LAL



large C-W structure exists



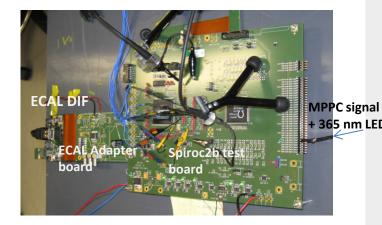




# V. Extension to other chips (T2K, JUNO)

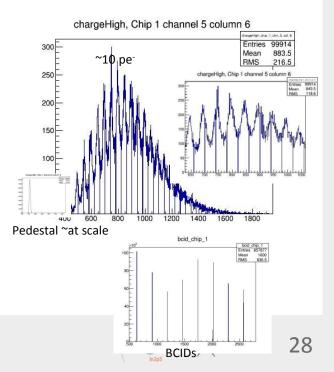
#### Test setup with a spiroc2b

- Use of a modified test board from Omega
- Fpga bypassed by an ECAL DIF
- ~<u>same DIF firmware</u> as for ECAL (modified pin-out and signal levels)
- MPPC + LED pulser (16 pulses within a spill)



#### **Combined tests**

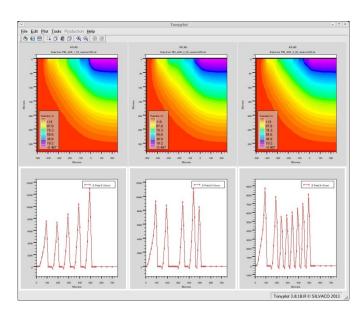
- Added an ECAL slab in the setup
- Common data acquisition as soon as SPILL signal is sent
- CCC : Same SPILL, same slow clock
- Events not in time (LED on one side, noise on the other) but cosmics would have been.
- Easiroc and Maroc will be added soon (started)

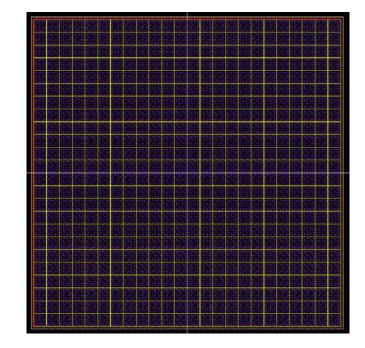


## Wafer R&D

#### Large size matrix burned on 8' wafers

- Ordered (LFOUNDRY)
- 700, 500 or 300 µm thickness
- 13.5 cm large
- 24\*24 pixels





#### **Segmented guardrings**

- Layout done at LLR
- From previous designs (baby wafers)
- Attempt to optimize structure by simulation





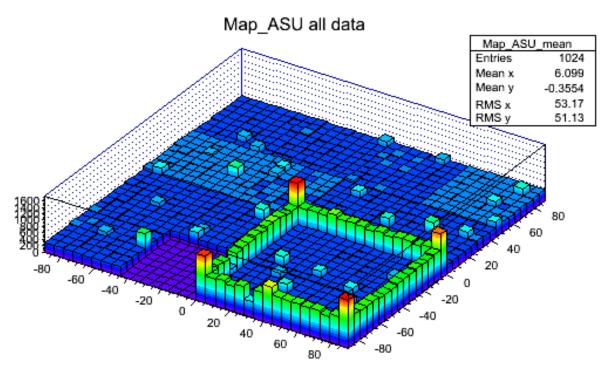
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## II.4 Square events



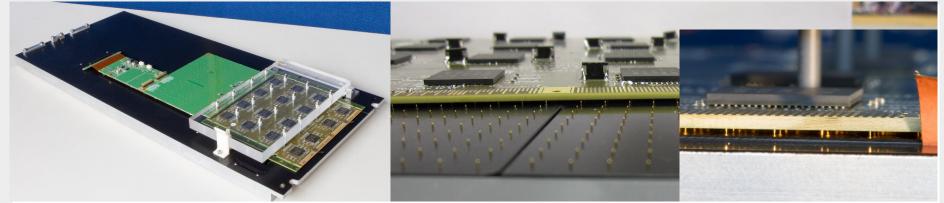
Infrared laser + fibre 20 ps light pulse FEV10 board + glued sensors (from 2009 batch)

All channels enabled (no masking), power pulsing Gain : 1.2 pF, Threshold : 400

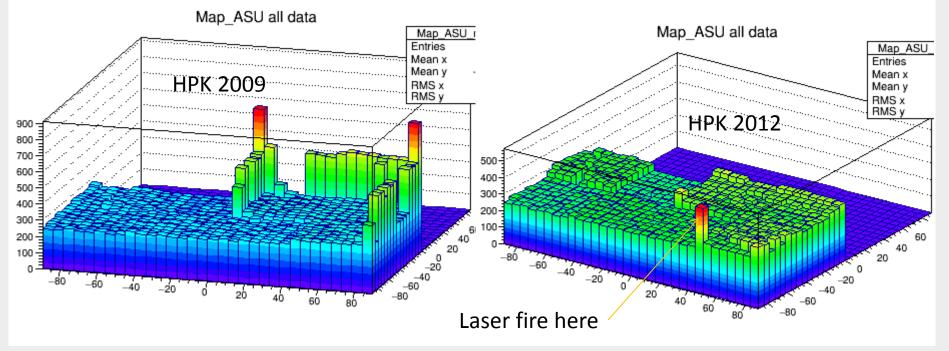




#### III. Desktop test setup with unglued sensors



Comparison of 2 different wafer design (with/witout guard rings) Missing signals (bad contacts with springs ?)







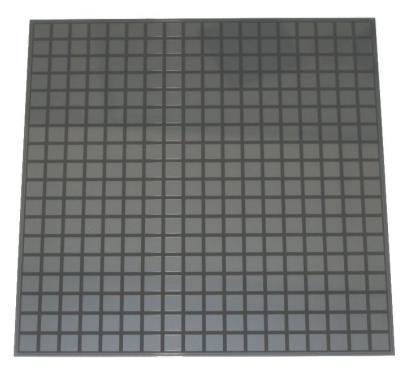
## P2IO/Captinnov Platform



1

# Example of an application

Map of leakage current of the 16 x 16 (9x9 cm<sup>2</sup>) PIN diodes detector for the CALICE/ILD Si-W ECAL







The scan is fully automated and the measurements are synchronized with the machine, Duration of the scan: 30 minutes for 256 diodes.

Map from the manufacturer (2011)

Measured map (09/06/2015 – preliminary –)

nA nA 22-20-18-16 14 12 10 10 8 6 4 2 0 2 Correlation Manufacturer 10

Measured

#### HPK WMap

#### WMap

# Conclusion





#### Preliminary tests of the first front-end board

LPNHE

All results should be checked will higher statistics and better methodology Signal over noise ratio seems to exceed design goal<sup>RunNum = 0, EventNum = 5401</sup> 98% of channels are responding (cosmics) Successful operations with **full** power pulsing Missing : linearity, crosstalk etc...

Production of a small batch of 8 slabs Gluing of sensors planed for end of May/June Assembly of slabs : September

Next engineering step is building a long detector module Requires specific studies of the power distribution Already tested 2 front-end boards together

